

**Notice of References Cited**

Application/Control No.

09/730,656

Applicant(s)/Patent Under

Reexamination

BOHMER ET AL.

Examiner

Douglas W Owens

Art Unit

2811

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-4,243,427	01-1981	DiBugnara, Raymond	106/287.16
X	B	US-5,053,992	10-1991	Gilberg et al.	365/185.04
X	C	US-5,258,334	11-1993	Lantz, II, Leon	438/760
X	D	US-5,892,661	04-1999	Stafford et al.	361/737
X	E	US-6,144,106	11-2000	Bearinger et al.	257/789
X	F	US-2002/0033486	03-2002	Kim et al.	257/118
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
X	U	Laura Peters. September, 1998. Semiconductor International. "Pursuing the Perfect Low - k Dielectric.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.